INTRODUCTION

DIFFUSION AND DEFECT DATA aims to combine the advantages of abstract publications with the considered presentation of handbooks. Each volume contains some 600-1200 extended abstracts, with important data presented in the form of graphs and tables. Within each volume, the information covered is arranged succinctly by both material and property. In addition, cross-indexing ensures rapid access to all aspects of the new research results reviewed.

These extended abstract handbooks represent a further step forward in containing the information explosion: the usual abstract periodical tends, more and more, to bury important new information under the sheer bulk of papers and reports to be processed. Handbooks, on the other hand, tend to be years out of date at the moment of publication. DIFFUSION AND DEFECT DATA combines the speed of abstract publications with the thorough presentation of handbooks. All aspects of solid state diffusion (including diffusion in liquids which are solid at normal temperatures and pressures) and the defect solid state (including irradiation effects) are covered.

DIFFUSION AND DEFECT DATA has now been published for 13 years. Since 1979, separate volumes have appeared covering metallic and non-metallic materials. It is hoped that this sub-division has helped researchers to assimilate, even more rapidly, recent advances in their particular field. Past experience has shown that the series fulfils this task and helps scientists to keep abreast of new developments. Overleaf are typical comments taken from book reviews and from letters received by the editor.

"A publication of this type fulfils an obvious need. The task of sifting the veritable mountain of published papers for useful nuggets of information grows more difficult and time-consuming each year. The availability of a publication which sorts the literature and classifies papers according to the materials and properties studied is a real boon to workers in this field. The reviewer found five recent papers of interest in as many minutes, and a colleague working in an entirely different field reported a similar experience. The typography is clear and pleasing to the eye, making the volume very easy to use.... A publication which is a useful reference source for anyone interested in defect phenomena, at a price not significantly higher than some of the journals which it surveys."

I.Lowe, J.Appl.Crystallogr.

"For anyone requiring information on current results and experimental techniques in the field, the series offers the best possible method at present available for obtaining such information quickly, conveniently, and reliably."

C.Herzig, Angew.Chemie Intl.Ed.

"A precious source of information....The references are quite exhaustive and up-to-date...Certainly an asset to all libraries and institutions."

K.S.Raman, J.Electrochem.Soc.India

"The books make a very orderly and agreeable impression. Some checks on the completeness and reliability of the information did not yield any complaints... The subscription is highly recommended."

W.Eichenauer, Ber.Bunsenges.Phys.Chem.

F.J.P.Clarke, J.Mater.Sci.

"An excellent periodical...I spend 1-2 two days with each volume when it arrives, and really catch up with the field, spending 2-3 days in the library looking up the most important references. This is in addition to later use."

SJR, Argonne National Laboratory

"These volumes present the data in a clear, concise way...."

HBH, Rensselaer Polytechnic Institute

Coverage is excellent and certainly the information is in a very convenient form."

ADLC, AERE Harwell

"The periodical is doing a great job, and with time will come to be depended upon very much by a wide variety of technical people."

LMS, University of North Carolina

"We rely heavily on your publication and eagerly look forward to each volume" DBB, US National Bureau of Standards

ABBREVIATIONS

The abbreviations used here for the journals, proceedings, and reports are the same as those used by "Chemical Abstracts", "Metals Abstracts", and/or "Physics Abstracts". When in doubt, the full journal title can be obtained from the lists periodically published by the latter journals.